

ABSTRACT OF THE DISCLOSURE

A redundancy fuse circuit including a function of replacing a defective cell in a memory cell array with a redundancy cell, comprising a fuse circuit in which
5 an address of the defective cell or a block including the defective cell is programmed as a defective address by presence/absence of cut-off of a fuse, a data latch circuit which latches a signal supplied from a tester to program the defective address in a dummy manner, and
10 a comparator which replaces the defective cell with the redundancy cell based on an address signal supplied from the tester and an output signal of the data latch circuit at an operation confirmation time of the redundancy fuse circuit.